

Mini Workshop on "Characterization of High Brightness Beams"

Monday 26 May 2008

PITZ talks on data taking and data analysis - S3 (14:00 - 15:45)

time	[id] title	presenter
14:00	[8] Data taking, data analysis and results of emittance measurements at PITZ	STAYKOV, L.
14:45	[9] Analyzing SPARC data with PITZ analysis tools	RIMJAEM, S.
14:58	[10] Analyzing SLAC data with PITZ analysis tool	SPESYVTSEV, R.
15:11	[11] Analyzing FLASH data with PITZ analysis tools	ASOVA, G.
15:25	[12] Principal limitations and systematic deviations regarding the slit measurement method	KRASILNIKOV, M.